

## Special Issue

# Advances in Perceptual Image Quality Metrics

### Message from the Guest Editors

Advances are rapidly taking place in the imaging industry, with new products introduced to the market. To evaluate and benchmark image quality, objective image quality metrics have become very popular. This Special Issue aims to present new research on perceptual image quality metrics including but not limited to full-reference metrics, no-reference metrics, reduced-reference metrics, new databases for the evaluation of image quality metrics, pooling techniques, and perceptual models for use in image quality metrics.

#### Keywords

- image quality metrics
- perception
- quality assessment
- quality databases

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### Guest Editors

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### Deadline for manuscript submissions

closed (10 February 2022)



## Applied Sciences

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### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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### Editor-in-Chief

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